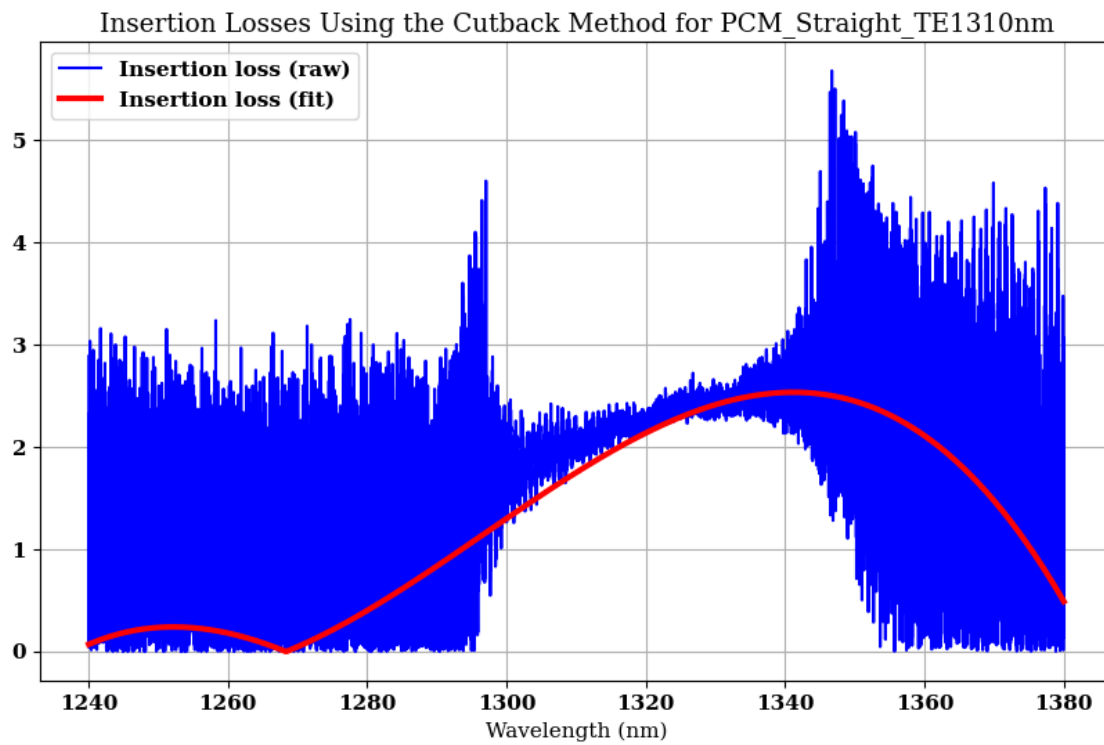
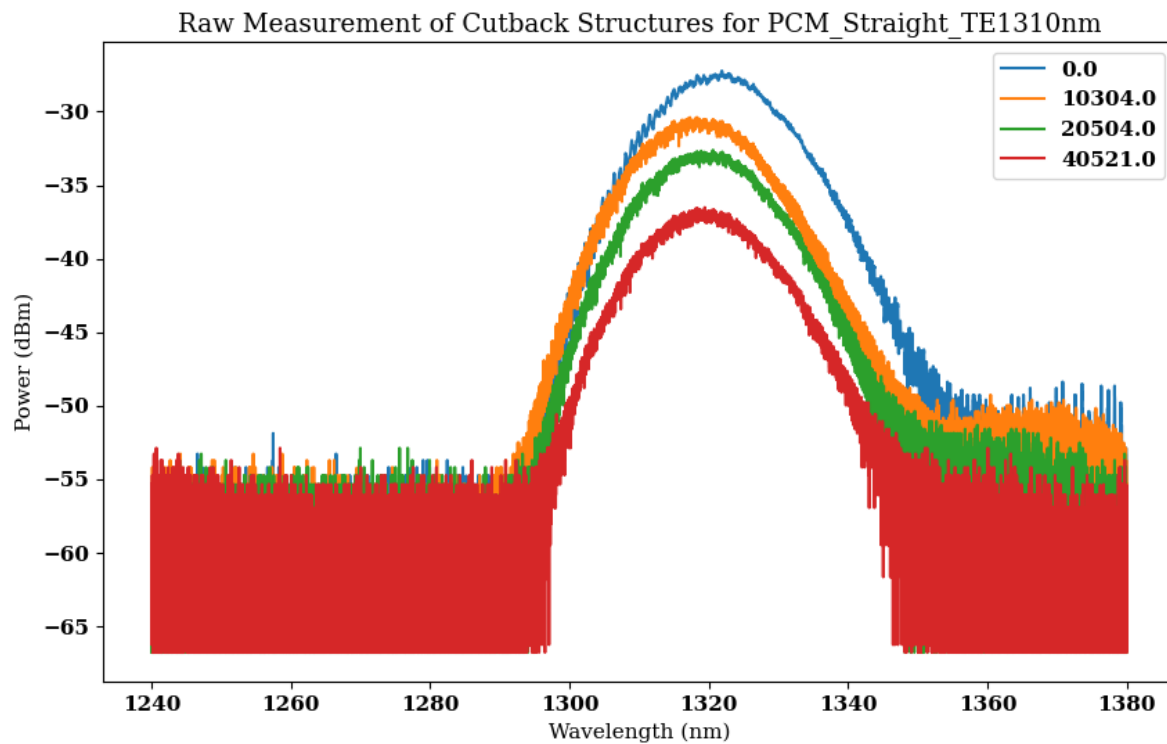


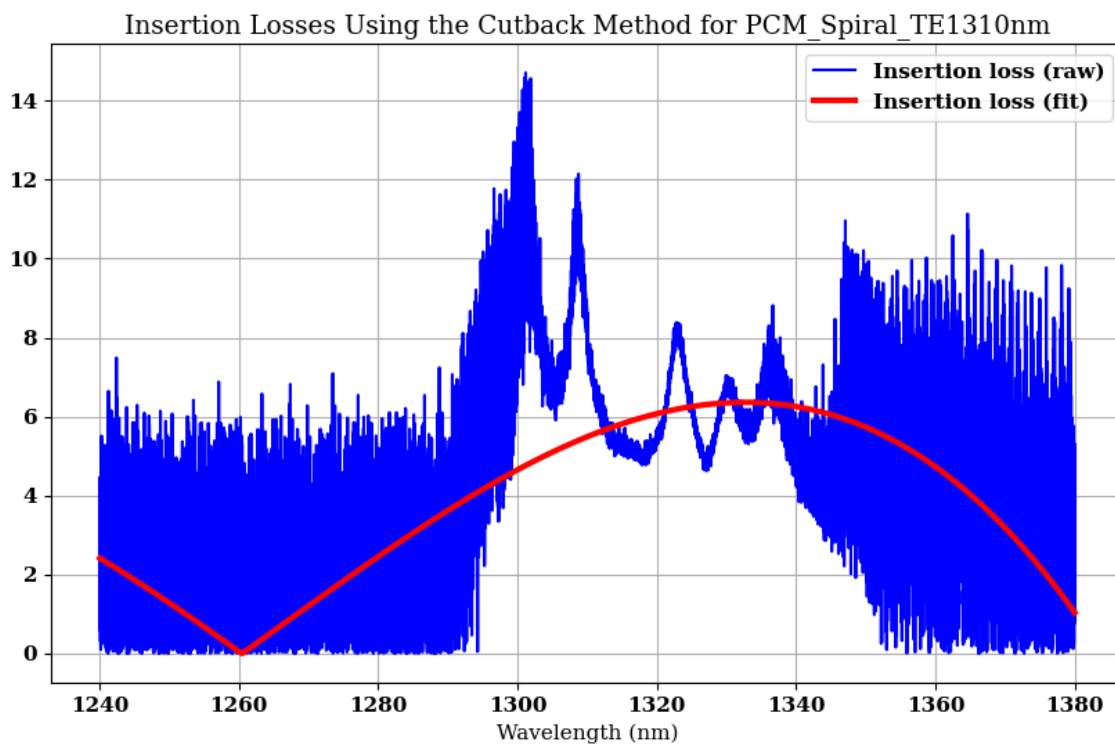
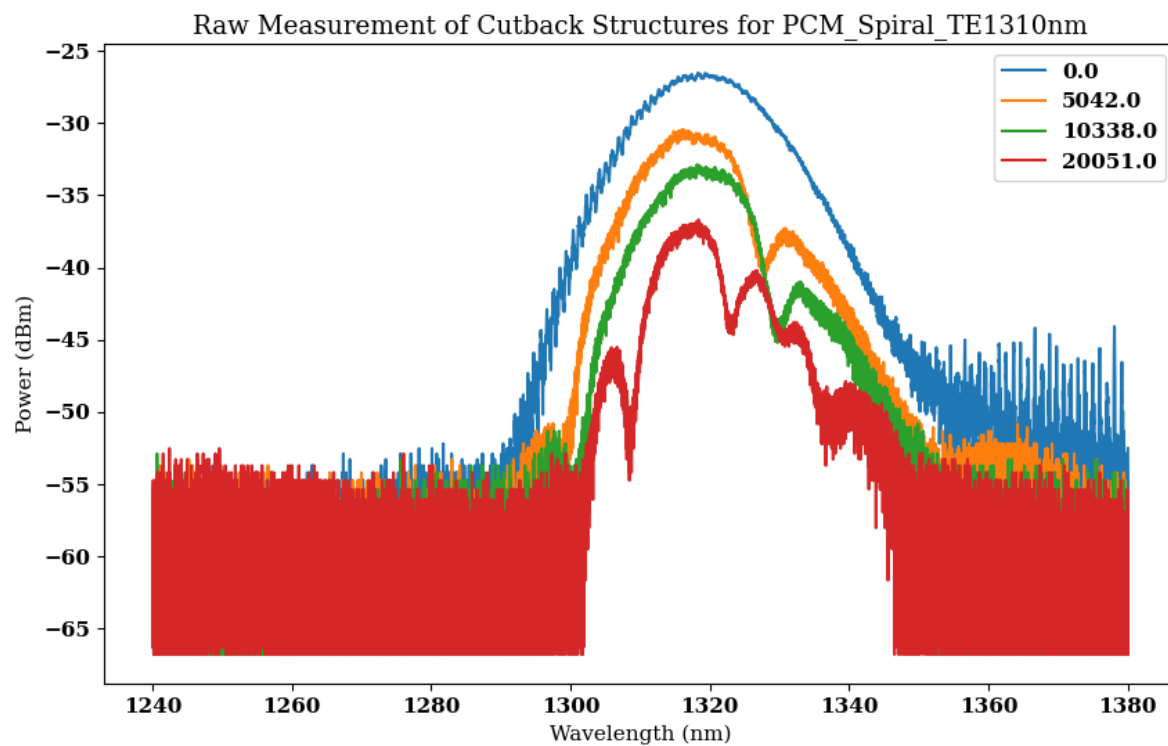
Analysis Report of EdX_May_2023_1310TE chip

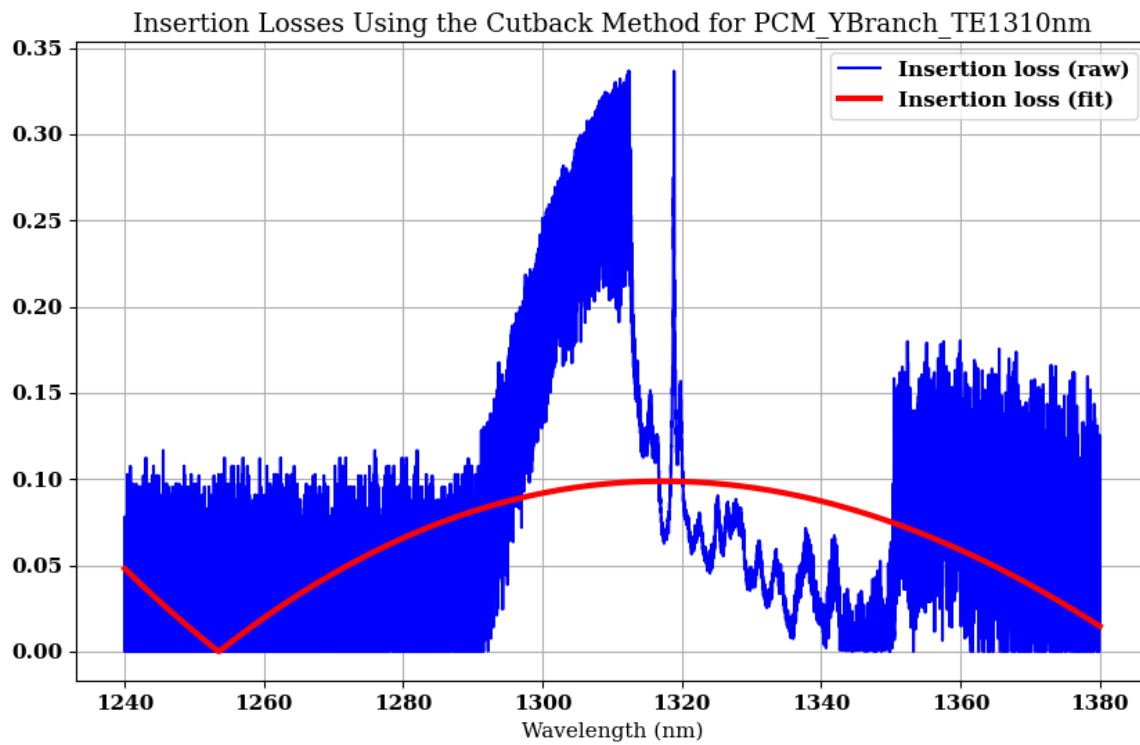
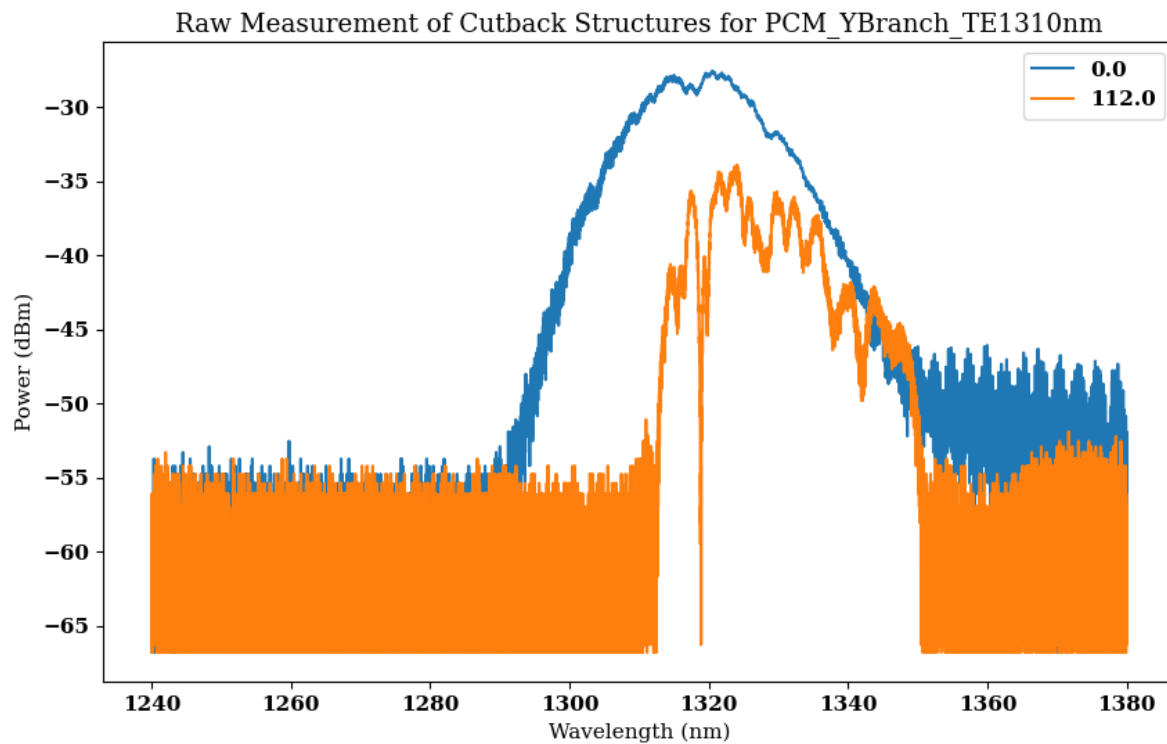
Measurement date: 2023-08-28

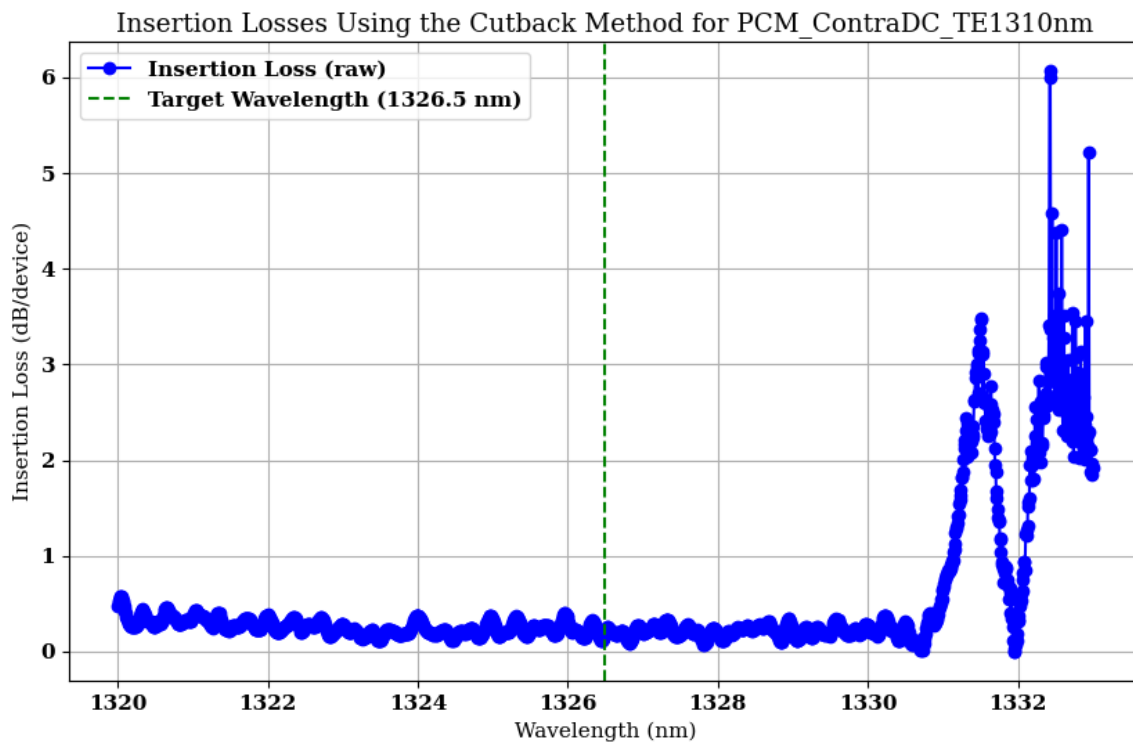
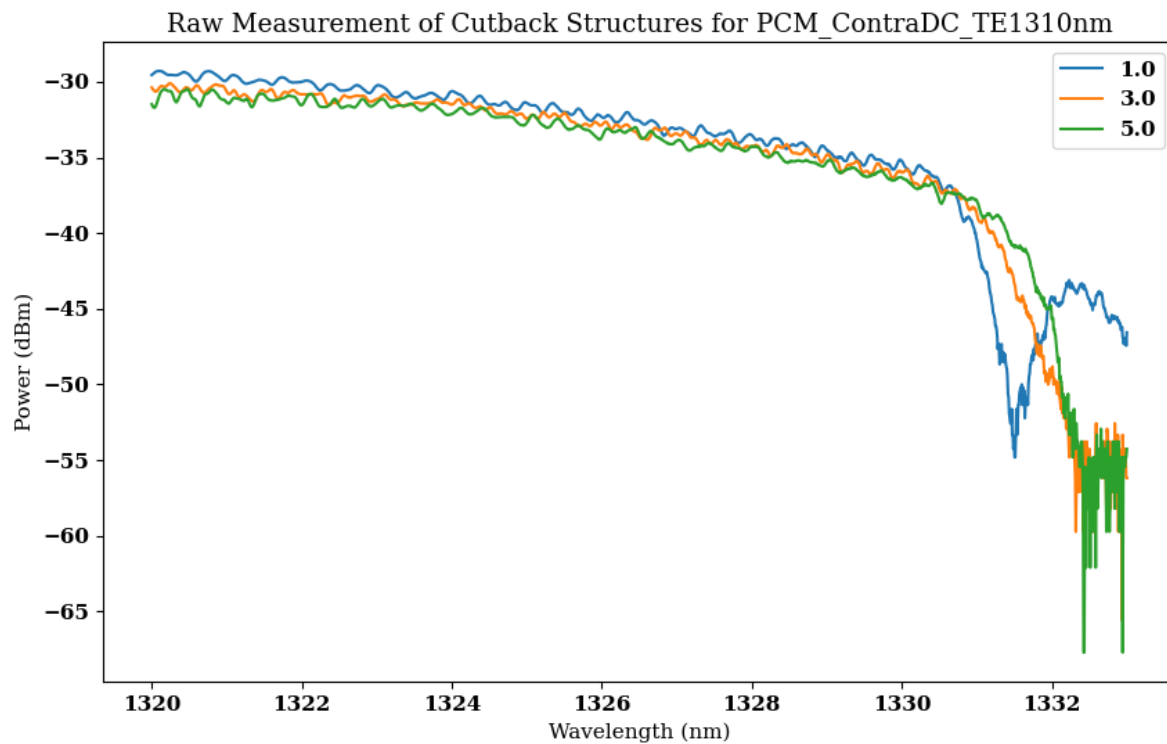
Process: ANT

Name	Wavelength	Polarization	Data	Error	Analysis
PCM_Straight	1310nm	TE	1.75	0.24	Insertion Loss (dB/cm)
PCM_Spiral	1310nm	TE	5.49	2.67	Insertion Loss (dB/cm)
PCM_YBranch	1310nm	TE	0.1	0.11	Insertion Loss (dB/device)
PCM_ContraDC	1310nm	TE	0.21	0.02	Insertion Loss (dB/device)
PCM_Bragg_Period	1310nm	TE	-0.71	N/A	Bragg Drift (nm)
PCM_GIndex	1310nm	TE	4.12	0.8	Group Index

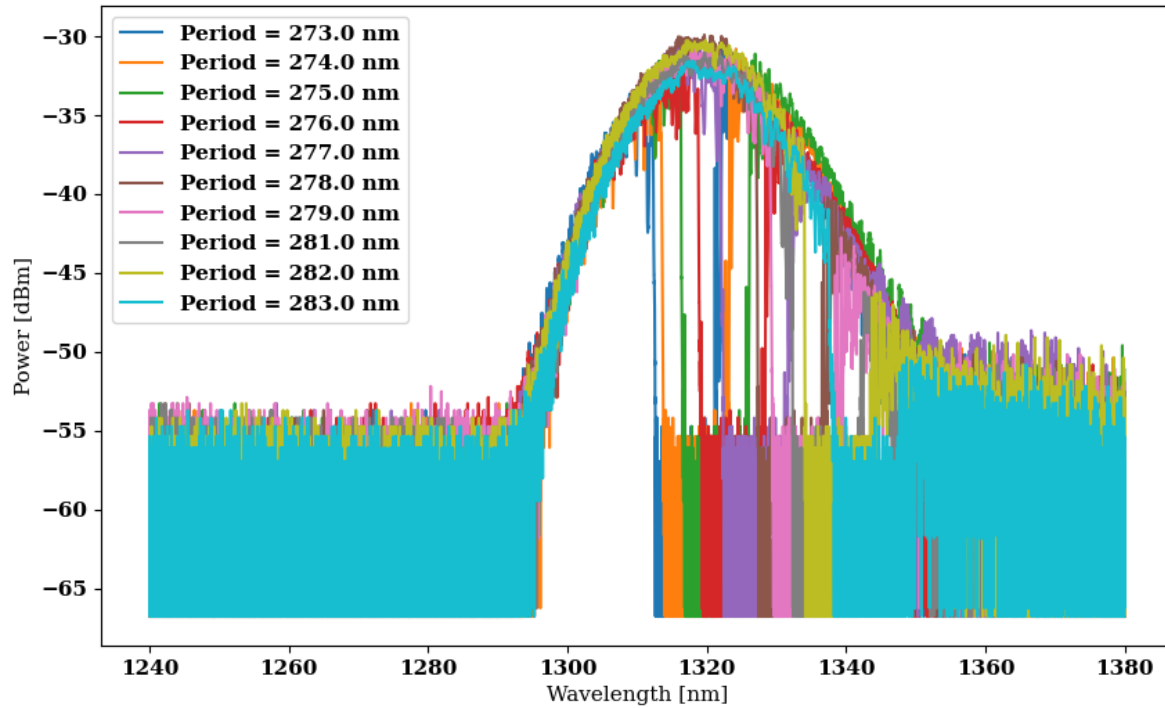








Raw measurement of all structures



Calibrated measurement of all structures (using envelope calibration)

